Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/718,192	KUO ET AL.	
Examiner	Art Unit	
Chris C. Chu	2815	

SEARCHED					
Class	Subclass	Date	Examiner		
257	E23.101, E23.087 & E23.119	9/25/2006	C.C.		
257	706 & 704	9/25/2006	C.C.		
257	790 & 738	9/25/2006	C.C.		
257	723 & 632	9/25/2006	C.C.		
257	717 - 720	9/25/2006	C.C.		
438	118 & 122	9/25/2006	C.C.		
174	52.4	9/25/2006	C.C.		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
As same	as above	9/25/2006	C.C.		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	9/25/2006	c.c.	